

**Search Notes**

Application/Control No.

10/664,500

Examiner

Maikhanh Nguyen

Applicant(s)/Patent under  
Reexamination

YALOVSKY, MARK

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	530	5/5/2006	MK
715	517,519	5/5/2006	MK
715	520	5/5/2006	MK
707	100	5/5/2006	MK
Updated	Search	11/15/2006	MK
Updated	Search	6/13/2007	MK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search	5/5/2006	MK
West Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB)	5/5/2006	MK
West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout	11/15/2006	MK
West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout	6/13/2007	MK